



Cathodoluminescence – Let there be light

MAS-AMAS Topical Conference

October 24-28, 2011 NIST Gaithersburg, MD USA

The Microbeam Analysis Society and the Australian Microbeam Analysis Society are pleased to announce a special Topical Conference on Cathodoluminescence, which will bring together international expertise in the application of CL techniques to a wide variety of materials. CL techniques enable impurity and defect microstructures to be investigated with high sensitivity and resolution. There will be sessions on CL theory, best practice and the advantages of CL combined with other complementary techniques. There will be presentations by students and professionals. This conference is recommended for experts and novices alike.

Cathodoluminescence Topics to be covered

Theory and Modeling of CL generation

Multiple voltage and Quantification of CL

Advances in CL instrumentation, analysis techniques and CL databases

Applications: Geological samples, Semiconductors, Nanomaterials

High resolution CL in TEM

CL correlated with EBIC and EBSD

Sample preparation

Highlights

Hands on laboratory demonstrations of CL equipment

CL software & database - tutorials

Contributed poster session

Special M&M journal issue on Cathodoluminescence

Centrally located at NIST outside Washington DC

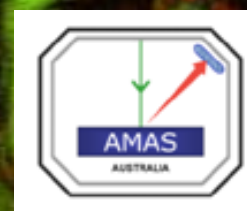
Social events and networking opportunities

Organizing Committee

Colin MacRae, CSIRO (Australia) colin.macrae@csiro.au

Marion Stevens-Kalceff, UNSW (Australia) marion.stevens-kalceff@unsw.edu.au

Scott Wight, NIST, scott.wight@nist.gov



Registration will be limited, to pre-register please send your name and email address to "CL2011@microbeamanalysis.org" and watch the MAS website <www.microbeamanalysis.org> for updates. Student support will be available.